

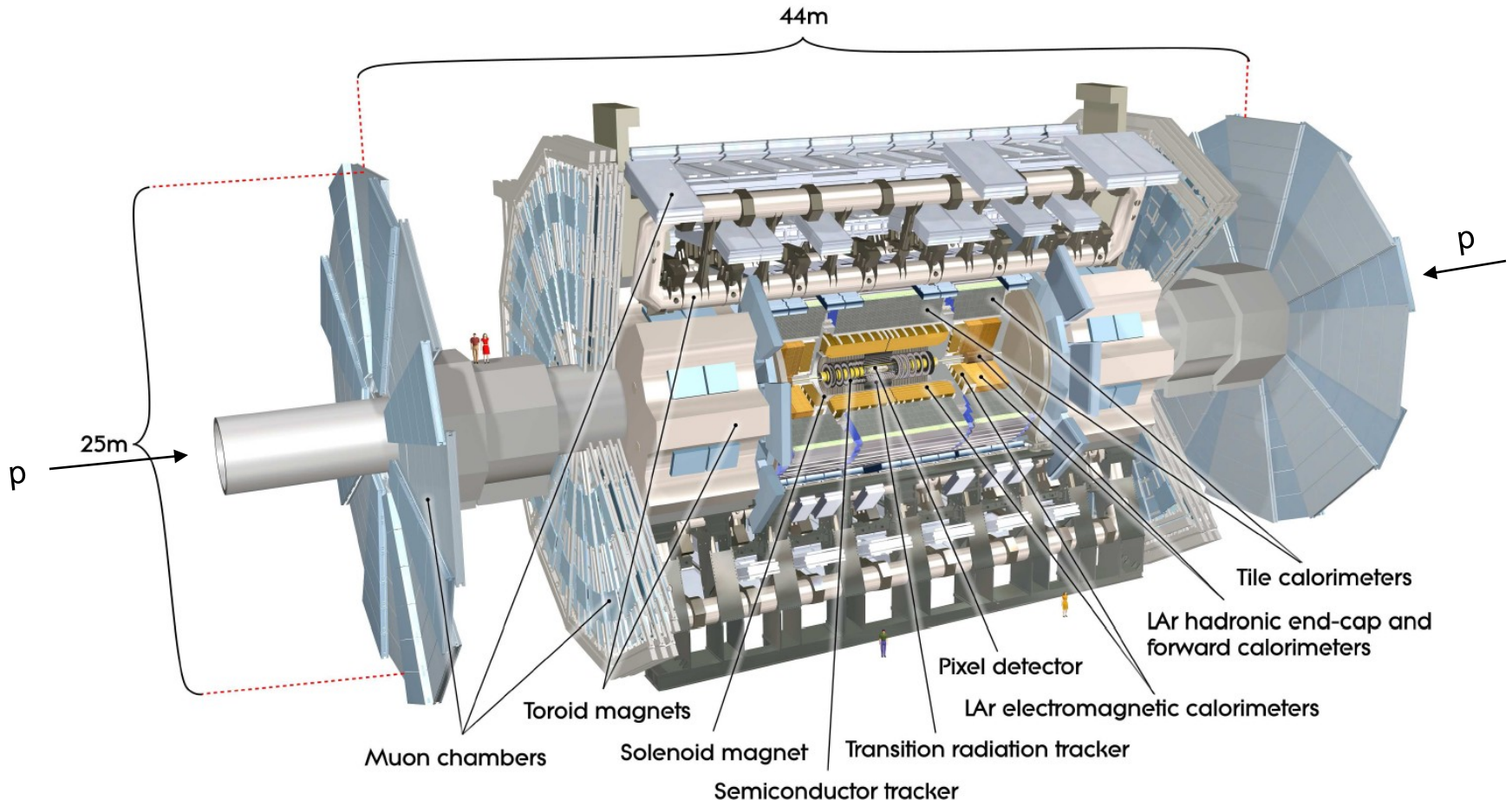
Online Radiation Dose Measurement System for ATLAS experiment

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The ATLAS experiment

- experiment at the Large Hadron Collider at CERN
- proton-proton collisions:
 - in 2011: $E_p = 3.5$ TeV, Peak Luminosity = 3.6×10^{33} cm⁻²s⁻¹
 - in 2012: $E_p = 4$ TeV, Peak Luminosity $\sim 6 \times 10^{33}$ cm⁻²s⁻¹
 - after 2014: $E_p = 7$ TeV, Luminosity $\sim 10^{34}$ cm⁻²s⁻¹

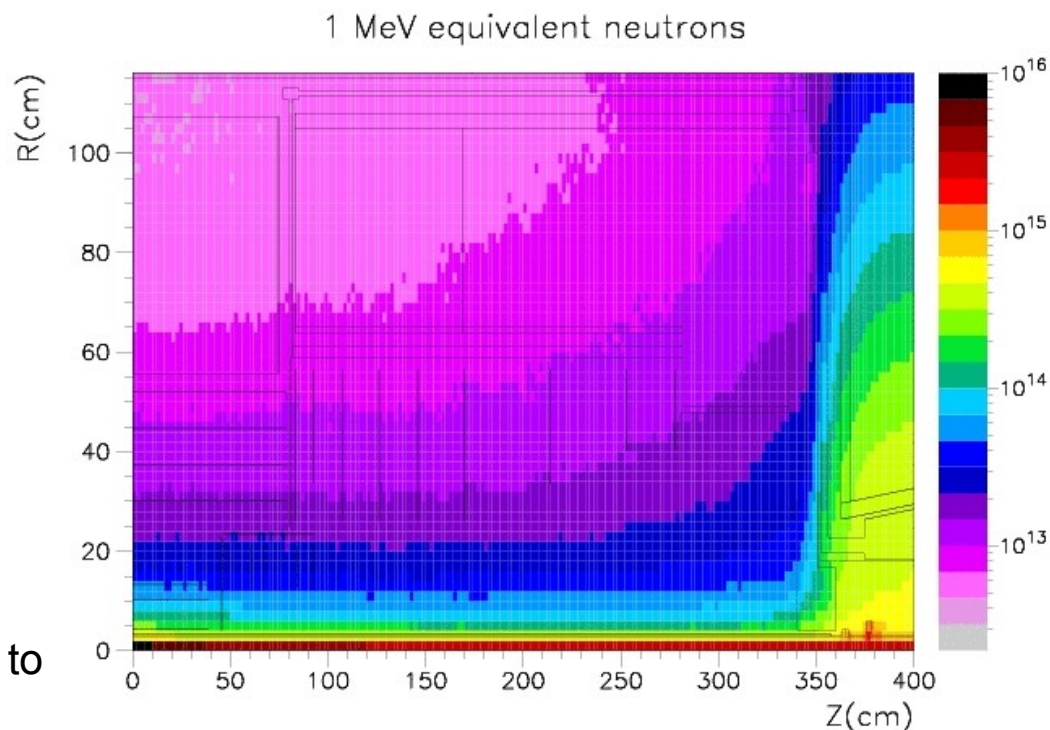


Radiation Field in ATLAS

- secondary particles from p-p interaction point - mostly pions
- radiation from interaction of secondary particles with detector material - neutrons

Expected radiation levels:

- Total Ionizing Dose (TID):
TID > 100 kGy
 - Non Ionizing Energy Loss (NIEL):
 $\Phi_{eq} > 10^{15}$ n/cm²
(1 MeV equivalent neutrons in Si)
 - Thermal neutrons $\Phi \sim 10^{15}$ n/cm²
- ➔ such radiation levels cause damage to detectors and readout electronics



Aim of radiation monitoring system:

- ➔ dose monitoring necessary to understand detector performance
- ➔ cross check of simulations and make predictions

Main Total Ionising Dose (TID) effect:

- radiation induced charge trapped in SiO₂ layer
- consequences:
 - change of threshold voltage in MOS transistors
 - leakage current between transistors
 - drop of gain in bipolar transistors
 - many more (e.g. attenuation in optical fibres)

Main displacement damage (Non Ionising Energy Loss: NIEL) effect:

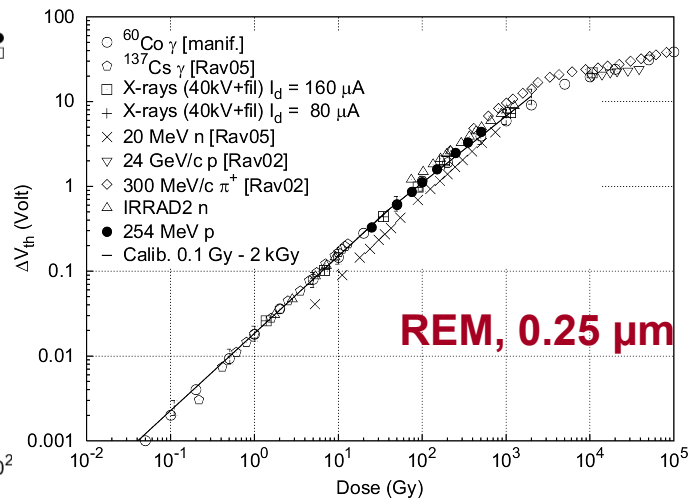
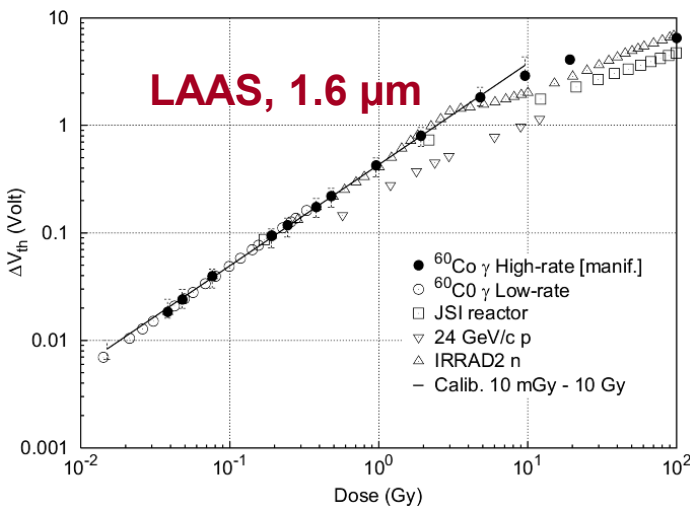
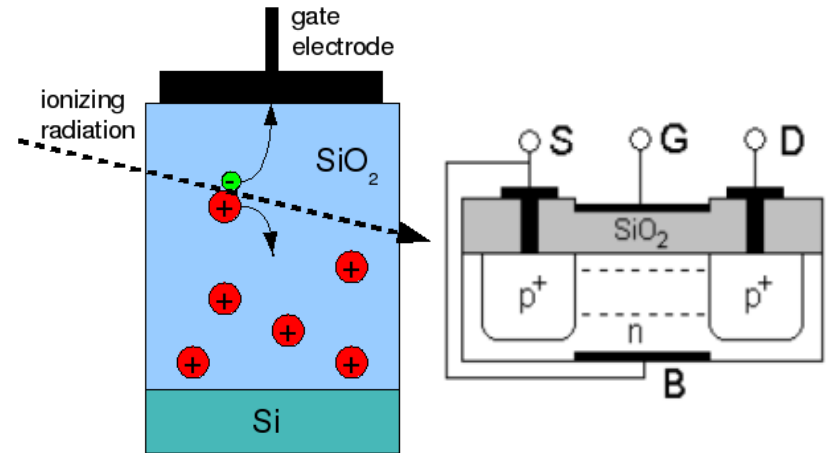
- energetic hadrons damage crystal lattice
- consequences:
 - increased reverse current in silicon detectors
 - increased full depletion voltage in silicon detectors
 - gain degradation in bipolar transistors
 - many more (e.g. degradation of responsivity in photo-diodes ...)

- ✓ detector components must be specially designed and selected for radiation environment
- ✓ accumulated doses must be monitored to understand detector performance

TID measurements with RadFETs

- RadFETs: p-MOS transistor
- holes caused by radiation get trapped in the gate oxide:
 - ➔ increase of threshold voltage with dose:

$$\Delta V_{th} = a \times (TID)^b$$
- sensitivity and dynamic range depend on oxide thickness:



Inner detector (high doses):

- 3 RadFETs at each monitoring location:
 - LAAS 1.6 μm; REM 0.25 μm;
 - REM 0.13 μm

Other locations (lower doses):

- LAAS 1.6 μm

- characterizations, selection, calibrations done by CERN RADMON team: F. Ravotti, M. Glaser, M. Moll.... (F. Ravotti ,PhD thesis, CERN-THESIS-2007-013)

NIEL measurements with diodes

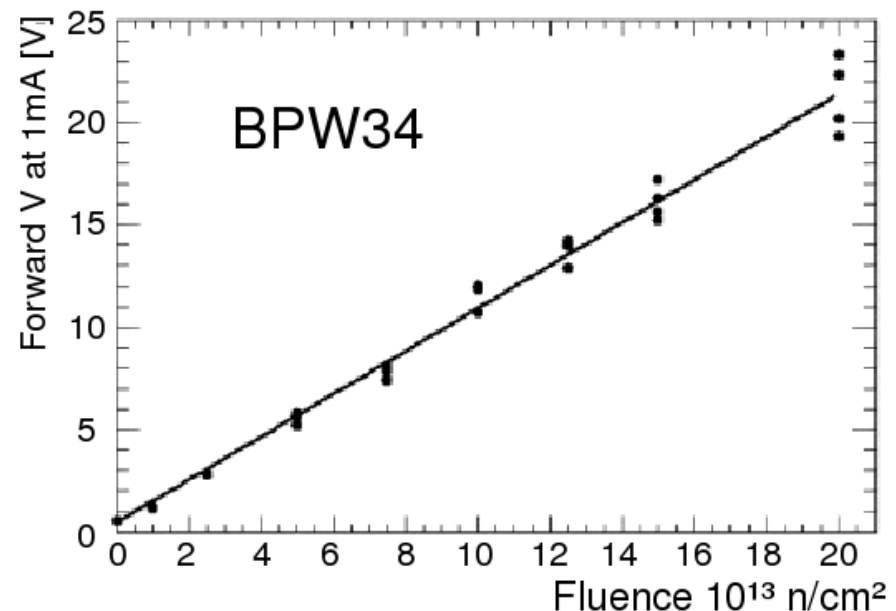
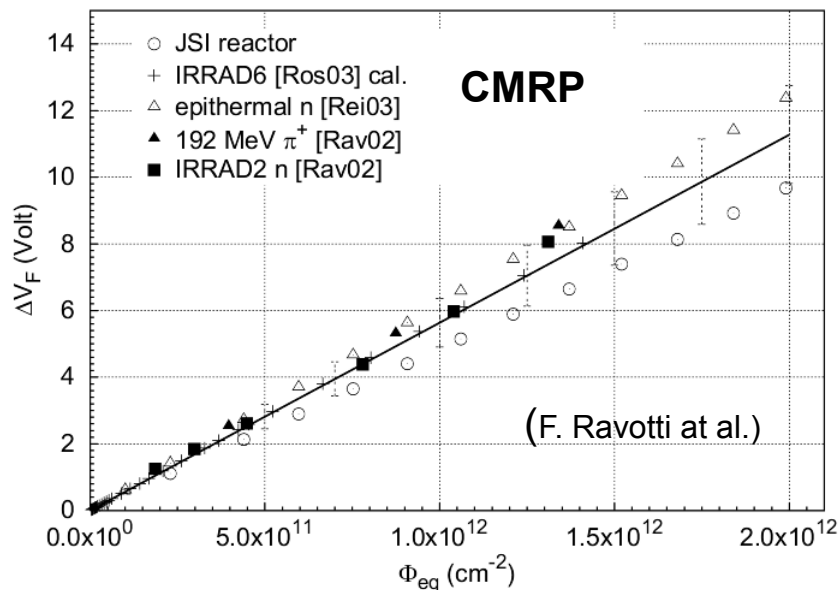
- displacement damage expressed in units of equivalent fluence of 1 MeV neutrons
- consequences of displacement damage (Non Ionising Energy Loss NIEL) in silicon:
 - increased resistance, reduced carrier lifetime, increased reverse current ...

Two methods for measurements with diodes:

- forward bias: voltage at given forward current increases
- reverse bias: increase reverse current

Forward bias

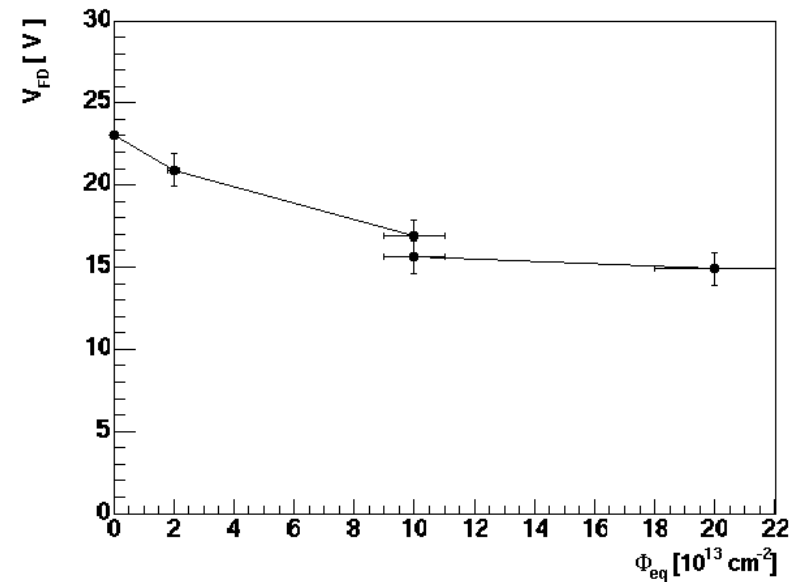
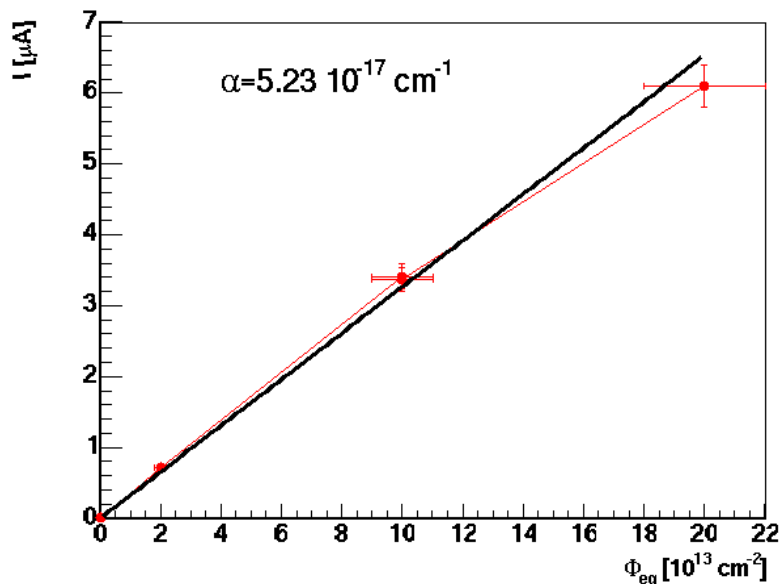
- linear response $\Delta V = k \cdot \Phi_{eq}$
- high sensitivity diode (CMRP, University of Wollongong, AU) 10^9 to $\sim 10^{12}$ n/cm²,
- commercial silicon PIN photodiode BPW34F 10^{12} to $\sim 10^{15}$ n/cm²



Reverse bias

Reverse current proportional to fluence $\Delta I = \Phi_{eq}/\alpha V$

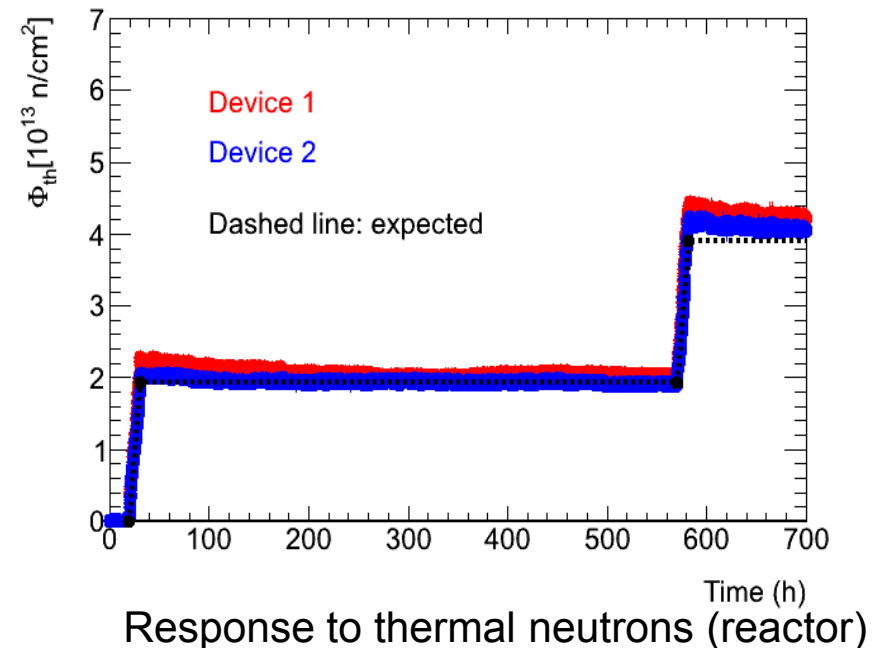
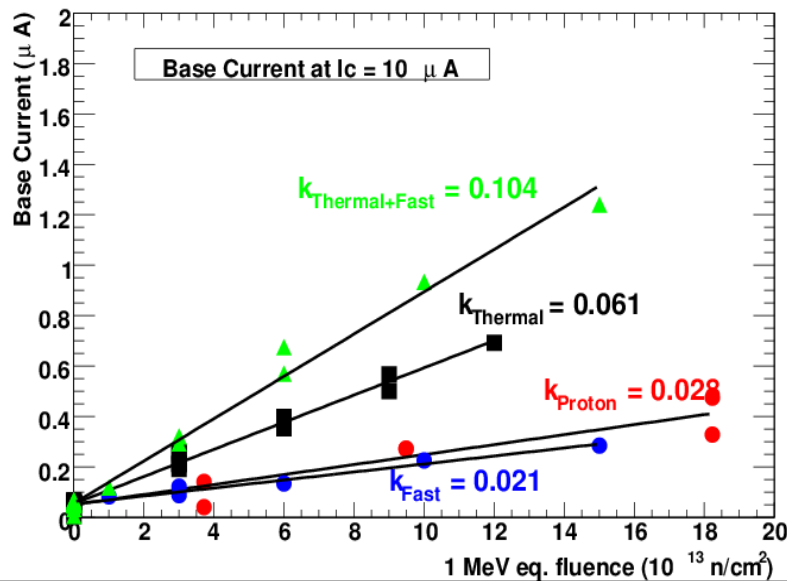
- **25 μm** x 0.5 cm x 0.5 cm pad diode with guard ring structure processed on **epitaxial silicon**
 - **thin epitaxial** diode can be depleted with $V_{\text{bias}} < 30$ V also after irradiation with 10^{15} n/cm²
 - in this fluence and time range V_{bias} does not increase with annealing
- suitable for fluences from 10^{11} n/cm² to 10^{15} n/cm²



Thermal neutrons

- bipolar transistors (DMILL) used in front end ASICs
- measure base current at given collector current
 - ➔ monitor status of front end electronics
 - ➔ sensitive to fast and thermal neutrons

$$\Delta I_b / I_c = k_{eq} \cdot \Phi_{eq} + k_{th} \cdot \Phi_{th}; \quad k_{eq}, k_{th} \text{ and } \Phi_{eq} \text{ known} \rightarrow \Phi_{th} \text{ can be determined}$$



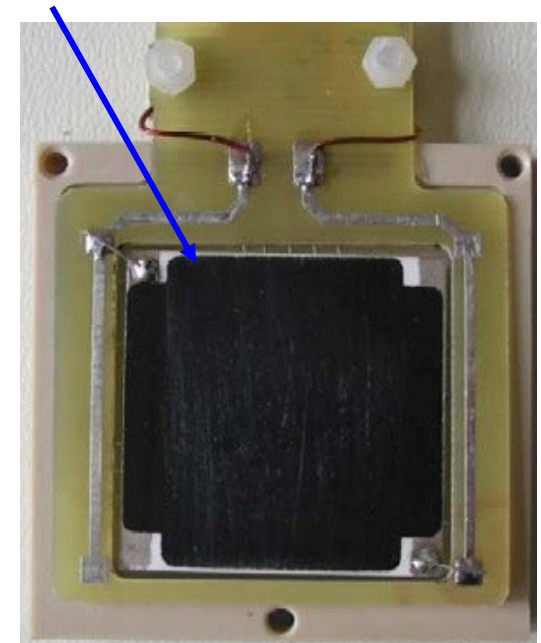
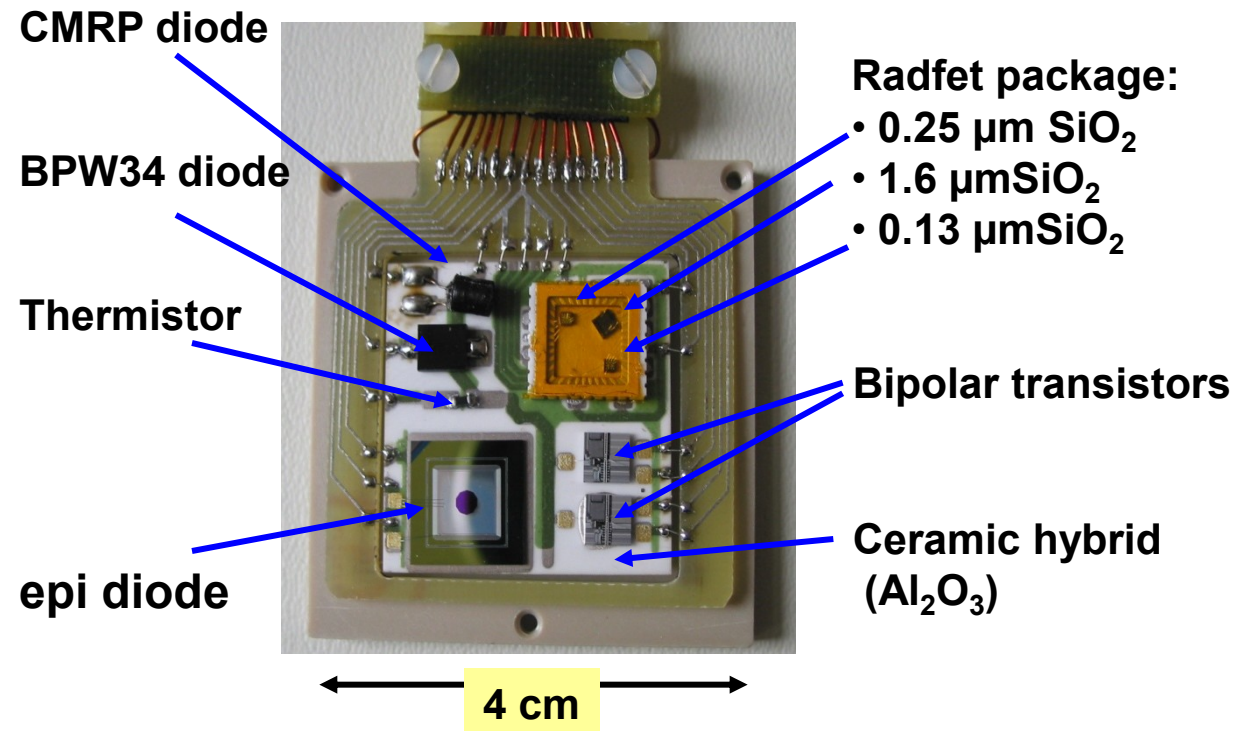
Radiation Monitor Sensor Board (RMSB)

Inner Detector

- for dose monitoring in the Inner Detector:
 - large range of doses
 - no access in 10 years
- **need many sensors**

- large temperature variations (5 to 20°C) at some locations
- stabilize temperature to 20 ± 1 °C by heating back side of the ceramic hybrid

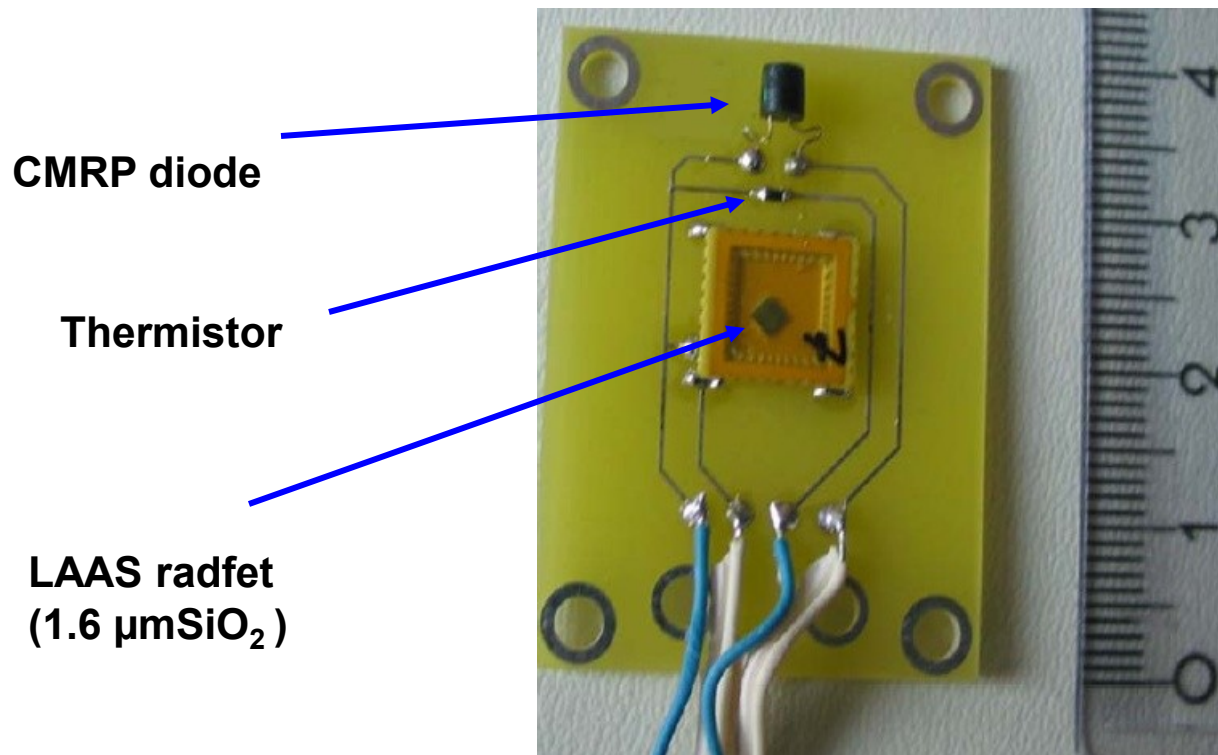
Thick film resistive layer $R = 320 \Omega$



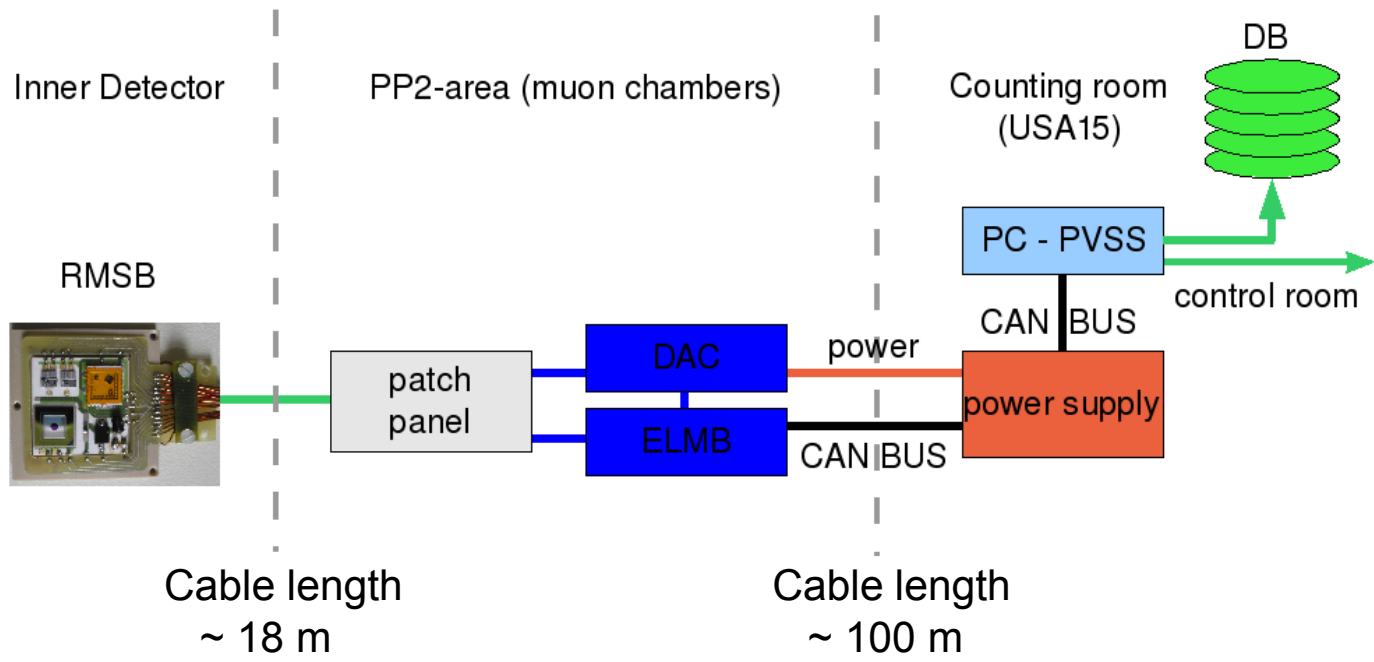
Radiation Monitor Sensor Board (RMSB)

Other locations

- lower dose ranges
→ mGy to 10 Gy, 10^9 to $\sim 10^{12}$ n/cm²
- no temperature stabilization
→ correct read out values with known temperature dependences

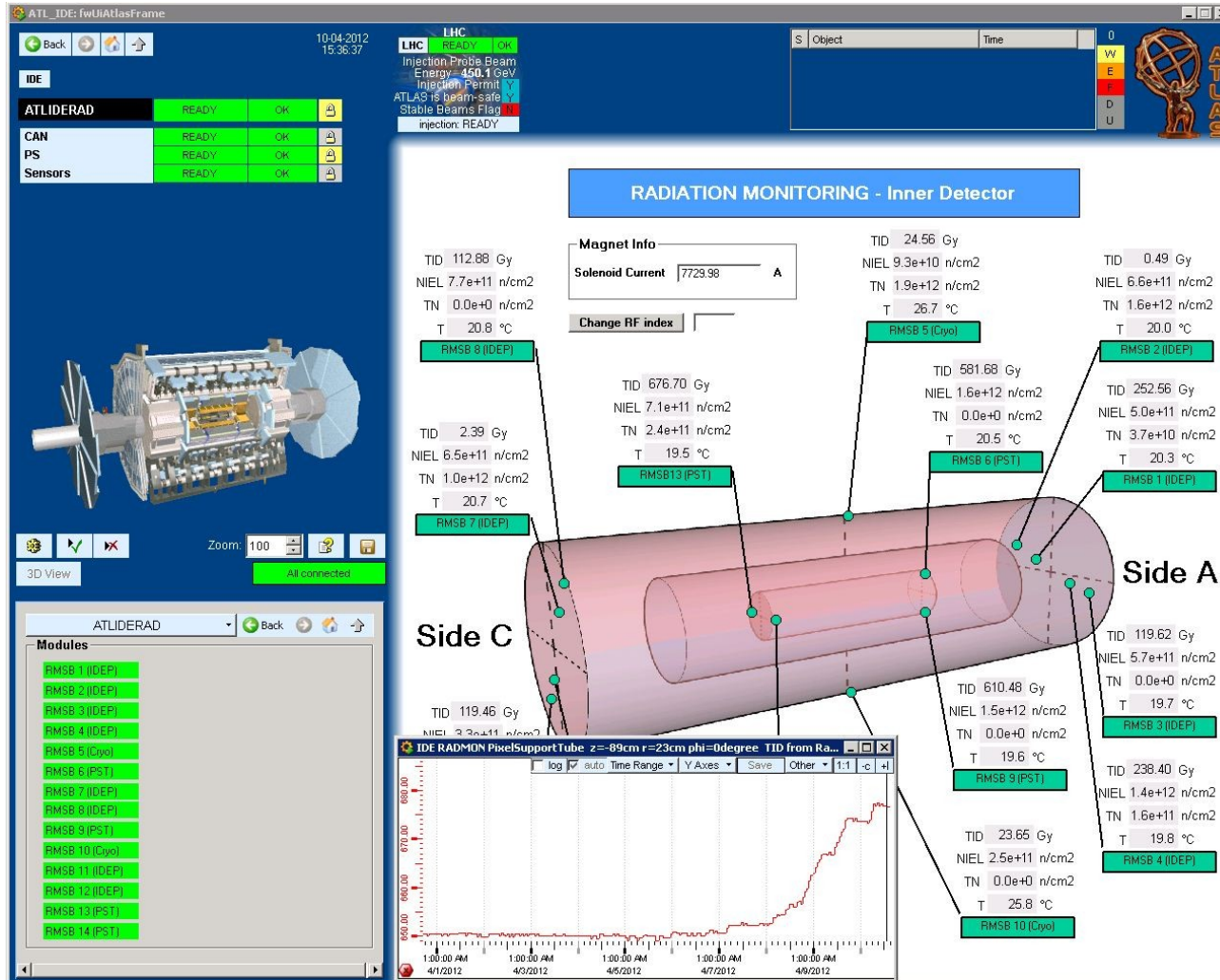


- use standard ATLAS Detector Control System components
 - **ELMB:**
 - 64 ADC channels
 - can bus communication
 - **ELMB-DAC:**
 - current source, 16 channels ($I_{\max} = 20 \text{ mA}$, $U_{\max} = 30 \text{ V}$)
- sensors are biased only during readout (\sim few minutes every hour)
- software written in PVSS



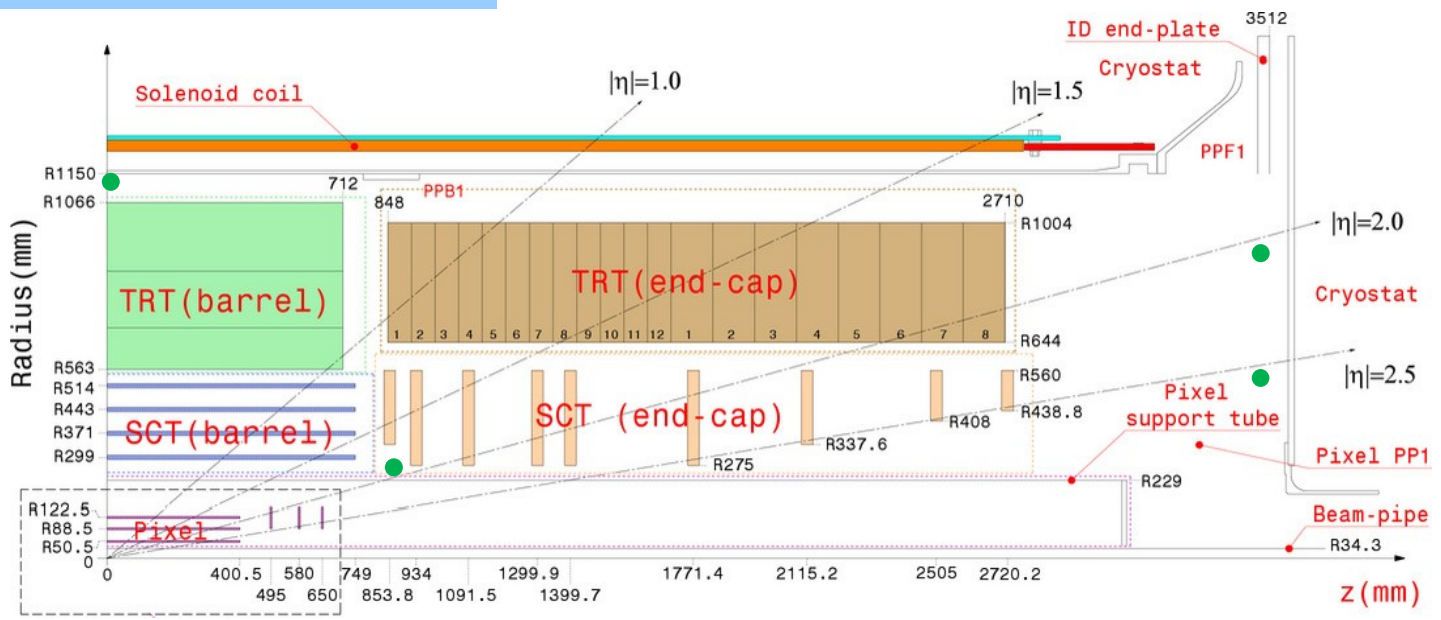
- Information about accumulated doses available online

Detector Control System Screen Shot:

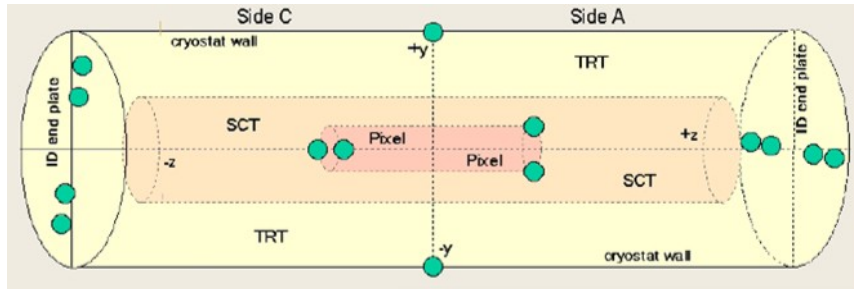


Monitoring Locations

- 14 monitors in the Inner Detector



Location	r (cm)	$ z $ (cm)
Pixel Support Tube (PST)	23	90
ID end plate small r	54	345
ID end plate large r	80	345
Cryostat Wall	110	90



Monitoring locations

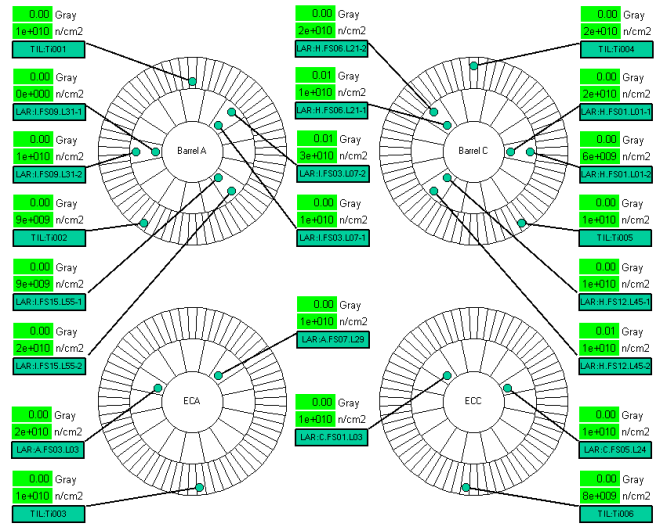
- 48 locations at larger radii
- 2 monitors very forward ($z = 240$ m, $r = 0.2$ m)

Calorimeters: 22

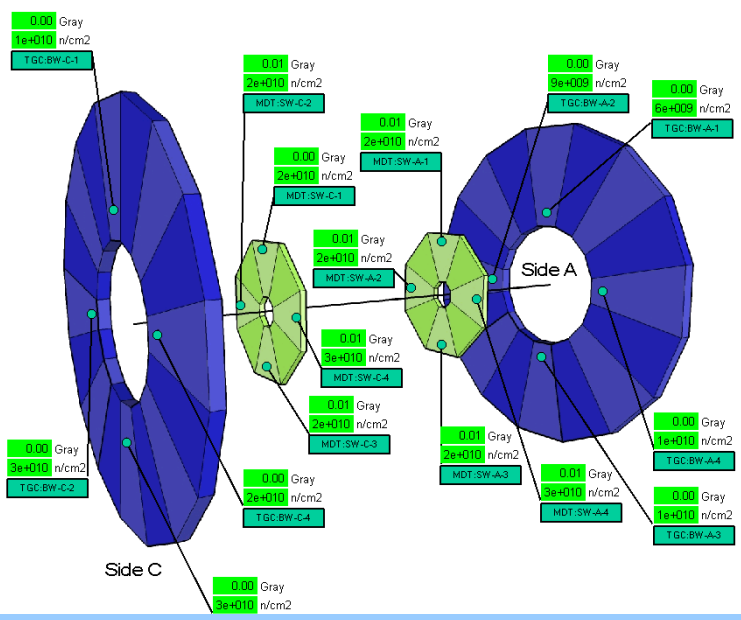
Muon detectors: 16

PP2: 10

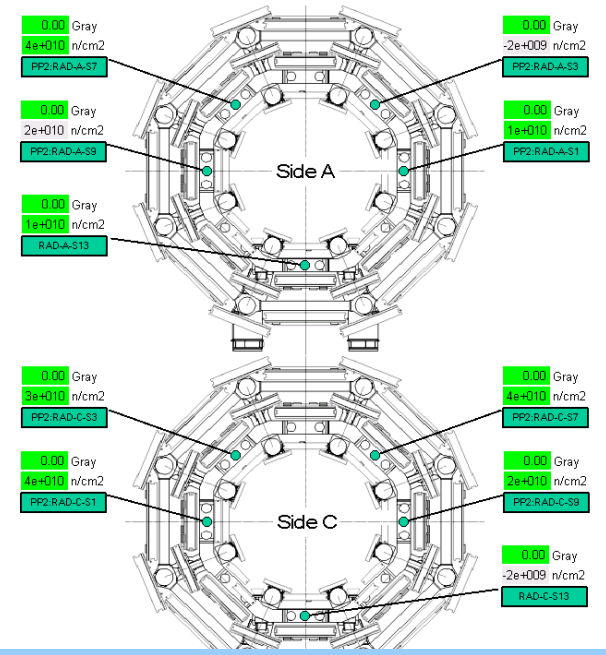
RADIATION MONITORING - Barrel and Extended barrels



RADIATION MONITORING - Big wheels and small wheel:



RADIATION MONITORING - PP2 areas



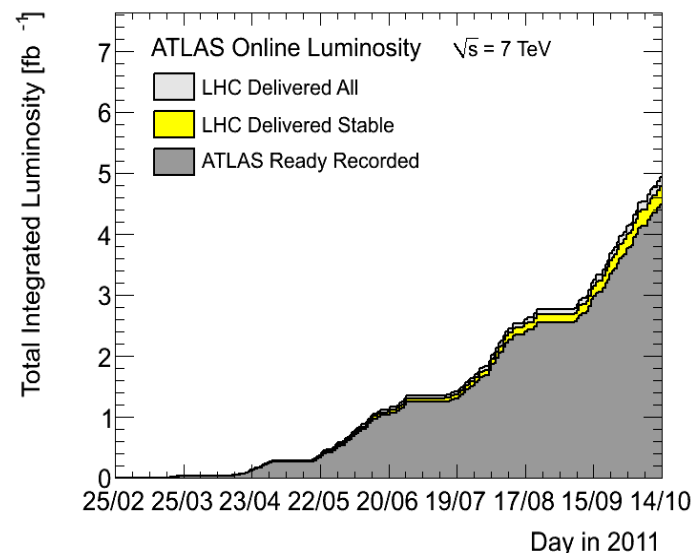
More in:

- I. Dawson and C. Buttar, "The radiation environment in the ATLAS inner detector", *Nucl. Inst. Meth. A453*, pp. 461-467, 2000.
- M. Bosman, I. Dawson, V. Hedberg, M. Shupe, "ATLAS Radiation Background Taskforce Final Summary Document", ATL-GEN-2005-001.
- I. Dawson et al., "Fluence and dose measurements in the ATLAS inner detector and comparison with simulation." ATL-COM INDET-2011-001

- FLUKA particle transport code
- PHOJET event generator
- simulations done for $\sqrt{s} = 7$ TeV assuming a proton-proton inelastic cross section 77.5 mb as predicted by PHOJET

Doses and fluences per fb⁻¹ of integrated luminosity

RadMon Location	Coordinates	Dose (Gy)	1 MeV equivalent neutron fluence (10 ¹¹ n/cm ²)
Pixel support tube	r = 23 cm z = 90 cm	110	2.22
Inner Detector End Plate – small radius	r = 54 cm z = 345 cm	55.4	2.24
Inner Detector End Plate - large radius	r = 80 cm z = 345 cm	27.0	1.35
Cryostat Wall	r = 110 cm z = 0 cm	4.9	0.45

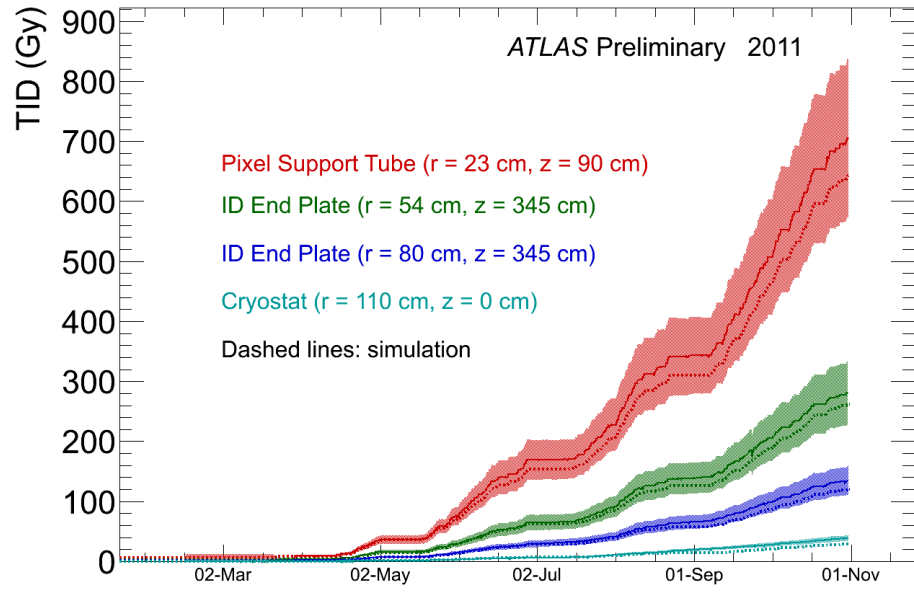
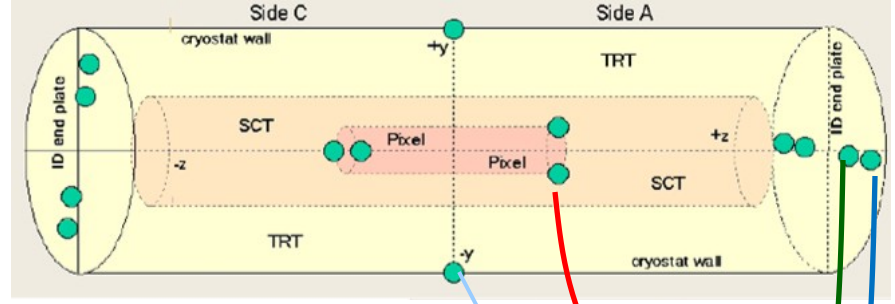


Integrated luminosity is a measure of number of proton-proton collisions

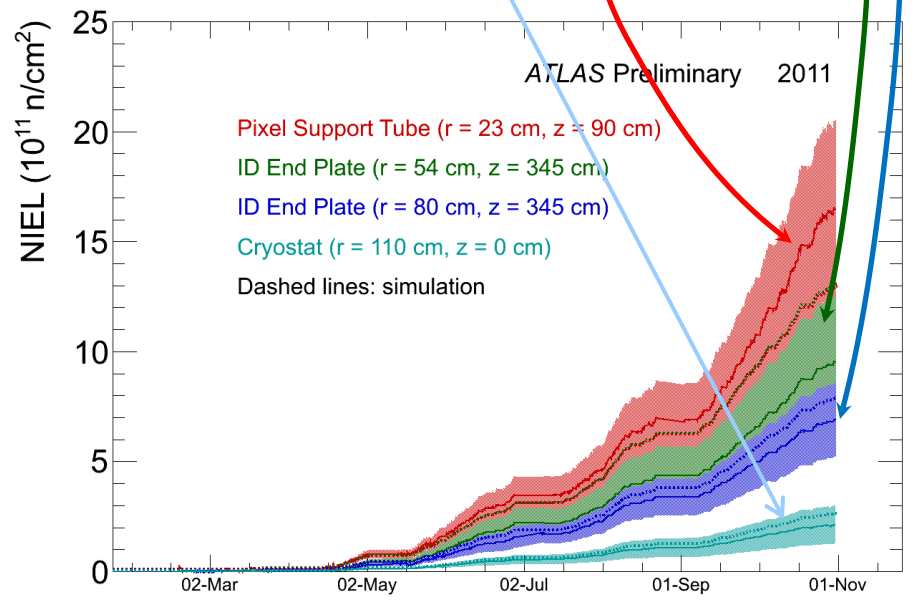
→ Simulated dose (fluence) = simulation factor × integrated luminosity

Results Inner Detector (ID)

- data up to 31st October 2011
 → Integrated luminosity ~ 5.6 fb⁻¹

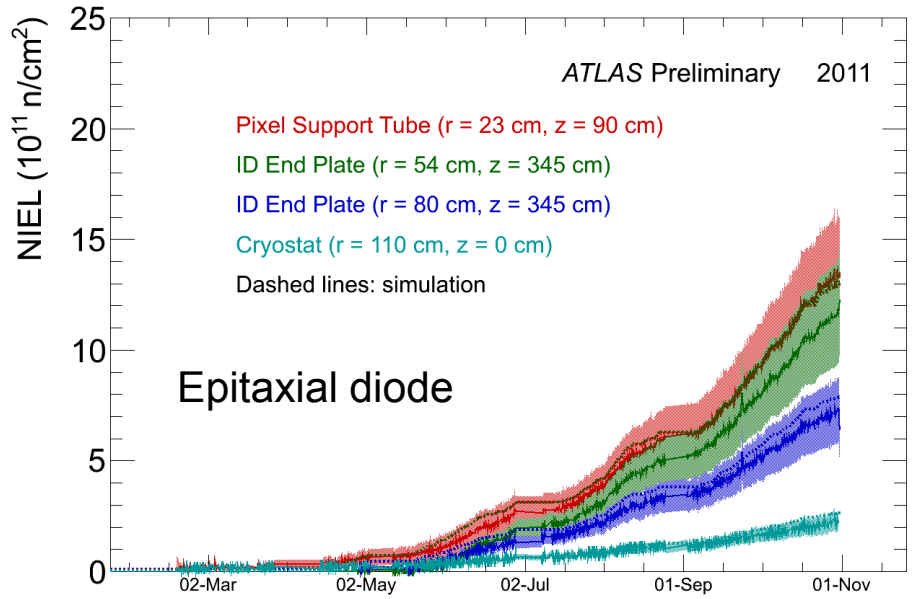


TID measured with 0.13 μ m RadFET (low sensitivity)



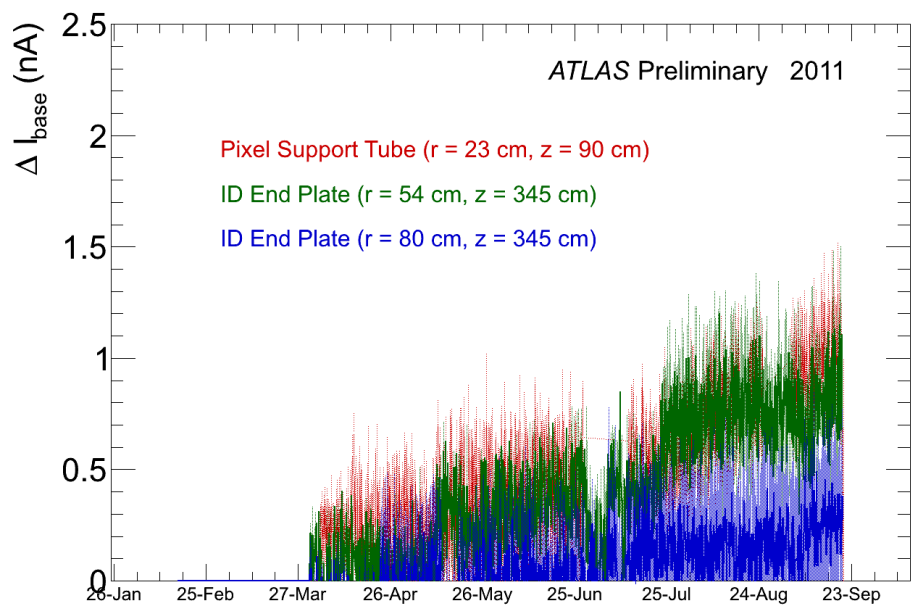
NIEL (1 MeV equivalent neutron fluence) measured with CMRP diodes (high sensitivity, forward bias)

- averages of measurements with sensors at similar locations are shown
 → excellent agreement with predictions!

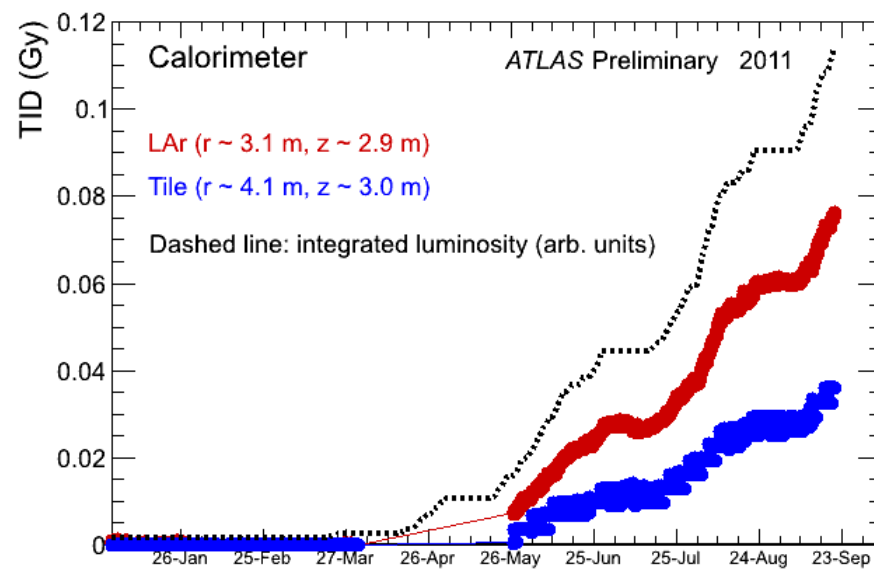
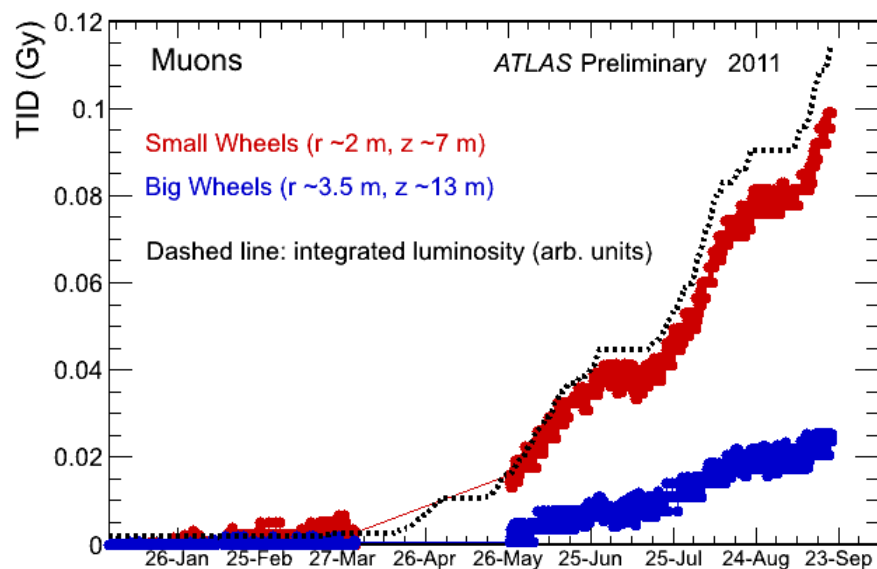


Good agreement with reverse current measurements with thin epitaxial diode

- first signs of base current increase in DMILL bipolar transistors
 - current increase consistent with thermal neutron fluence of the order of 10^{11} n/cm²
- in agreement with FLUKA



- outside of ID (radius > 2 m) doses still very low, on the limit of sensitivity
- accumulated dose proportional to integrated luminosity
- neutron fluences too low for reliable measurements



- measured doses and fluences proportional to integrated luminosity
- in the Inner Detector excellent agreement with predictions from FLUKA simulations
 - important for prediction of future detector performance
 - important for predictions for future High Luminosity LHC
- radiation damage already seen in detector components
 - increase of reverse current in silicon detectors
 - damage in agreement with FLUKA simulations